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Energy Efficiency
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Four Junction Solar Cell with 40% Target Efficiency Fabricated by Wafer Bonding and Layer Transfer

Subcontract XAT-4-33624-10

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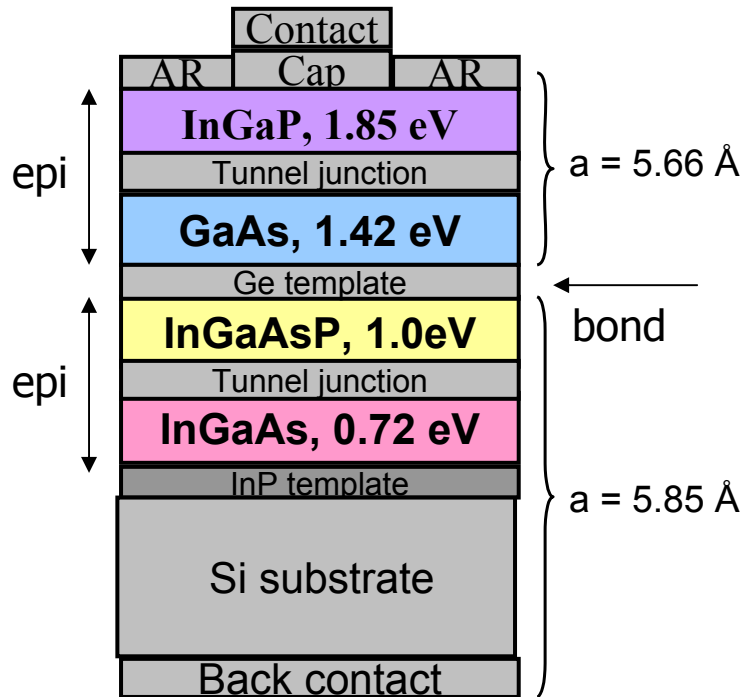
DOE Solar Energy Technologies Program Peer Review

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Research objectives:

1. Develop 4 junction solar cell for high performance photovoltaic receivers
2. Develop wafer bonding and layer transfer methods for integration of lattice-mismatched multijunction solar cells



4J Cell

- 2J InGaP/GaAs/Si cell on Ge/Si or GaAs/Si template
- integration of top and bottom cells by direct bond interconnect
- 2J 'bottom' InGaAsP/InGaAs cell on InP/Si template



- **Technical approach:**
 - Develop ‘top’ 2J InGaP/GaAs/Si cell (Caltech, Spectrolab)
 - Develop ‘bottom’ InGaAsP/InGaAs/Si cell (Caltech, Emcore, Aonex)
 - Perform integration of top and bottom cells (Caltech)
- **Participants:** Caltech, Spectrolab, Aonex, Emcore
- **Methods:**
 - wafer bonding and layer transfer to fabricate epitaxial templates for InGaP/GaAs growth and InGaAsP/InGaAs growth
 - MOCVD growth of InGaP/GaAs and InGaAsP/InGaAs
 - direct bond interconnection of top cell and bottom cell
- **Outcomes:**
 - Ge/Si and InP/Si template layer process development
 - GaAs/InP direct bond interconnect development
 - GaInP/GaAs/Ge/Si cell development
 - InGaAs/InP/Si development



Project Task(s)	Total Value
Phase 1 (8/04-8/05)	\$205,000
Phase 2 (8/05-8/06)	\$174,000
Phase 3 (8/06-8/07)	\$146,000
Grand Total	\$525,000



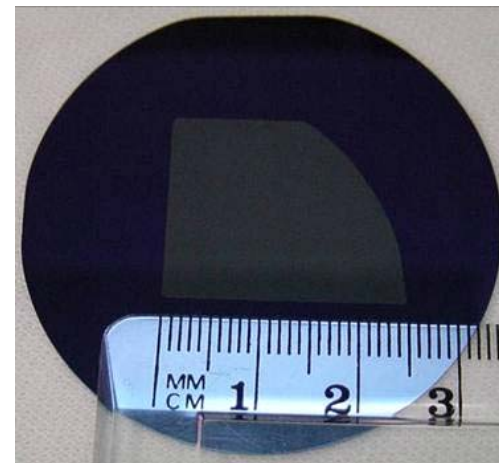
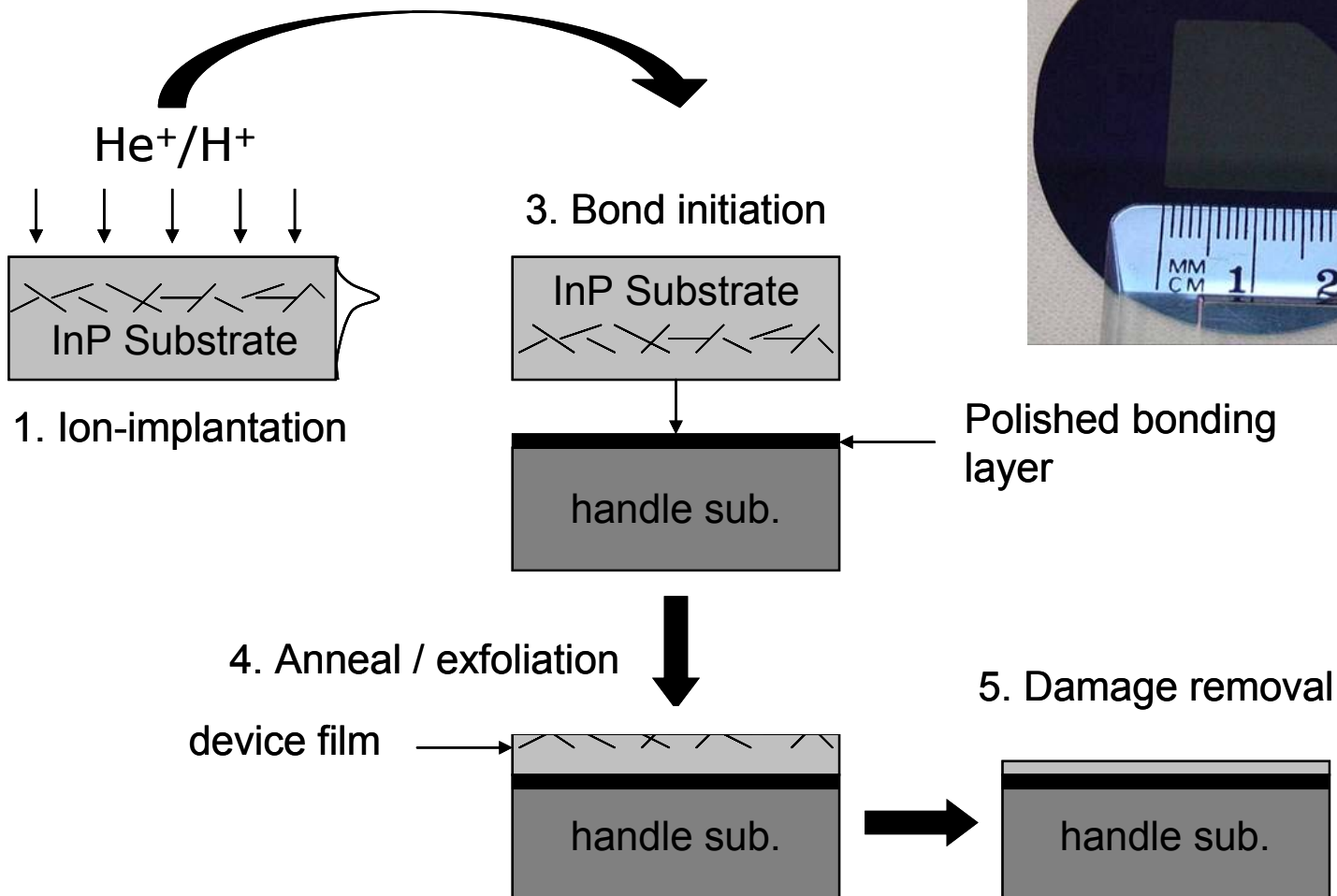
Accomplishments to Date:

1. 'top' 2J cell demonstrated
 - Ge/Si template is dislocation-free
 - MOCVD-grown InGaP/GaAs cells on Ge/Si are crack-free
 - Surface quality on Ge template is the gating issue for cell quality
2. bottom InGaAs/InP/Si cell with superior performance to InGaAs/InP demonstrated
 - Insertion of SiO₂ layer enables light trapping in InGaAs/InP template cell
3. Optimized InP/Si template layer process developed
4. Almost-optimized Ge/Si template layer process developed
 - Combined wet-etch/CMP process important for epi-ready surface quality



InP/Si Epi-template Fabrication

2. Cleaning / surface passivation

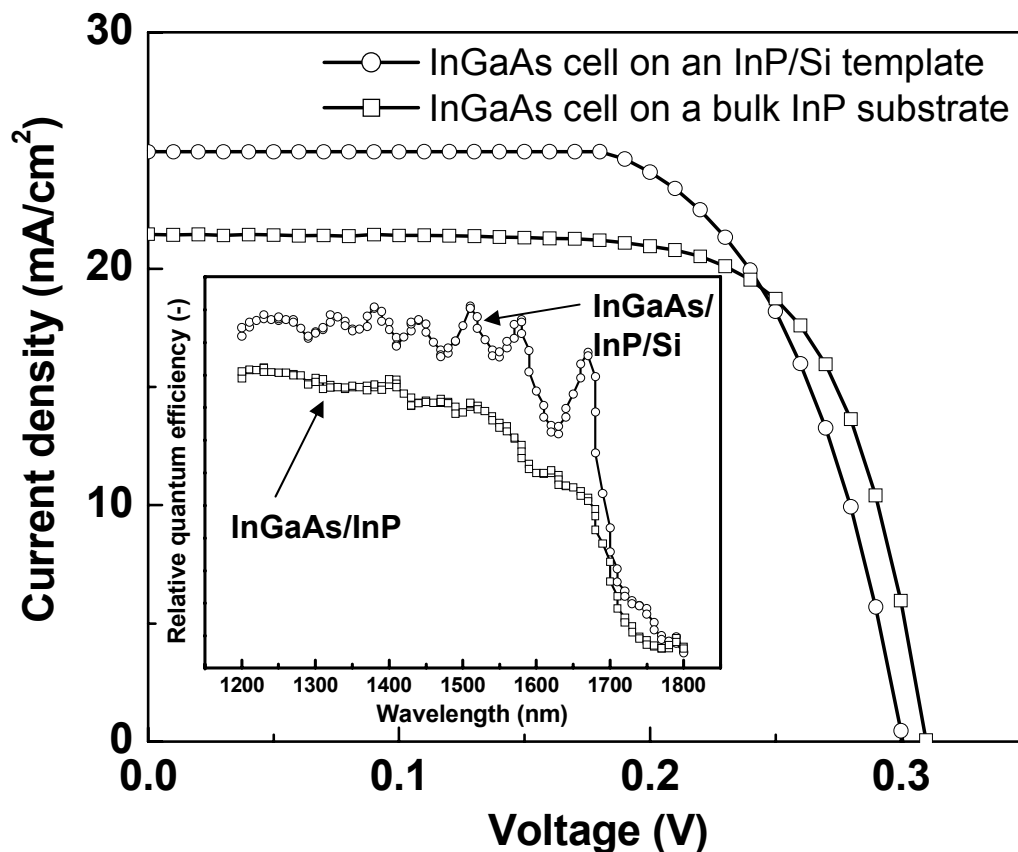
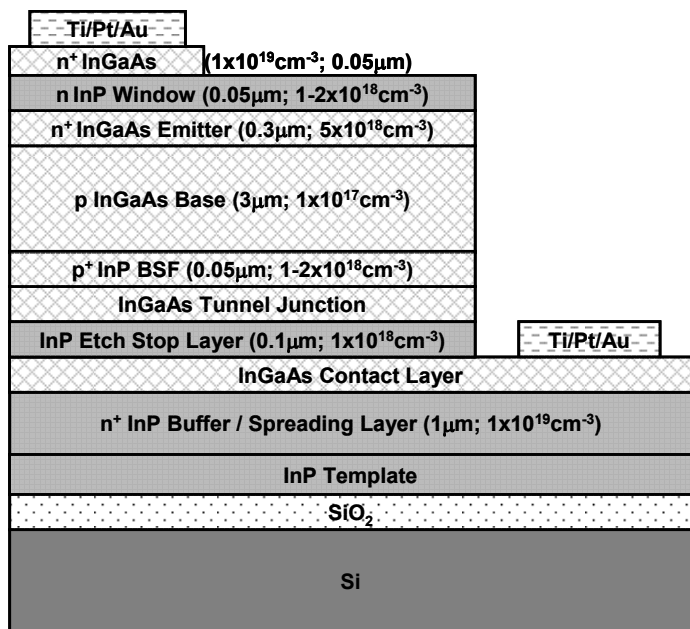




InGaAs/InP/Si Cell with Enhanced Photocurrent Collection Relative to InGaAs/InP

$n @ \lambda = 1400\text{nm}$

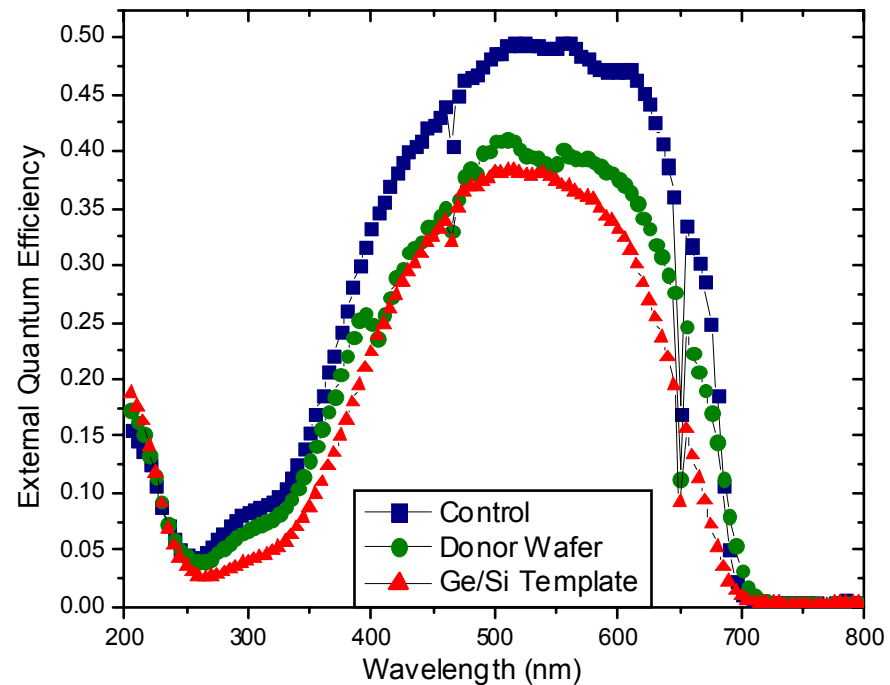
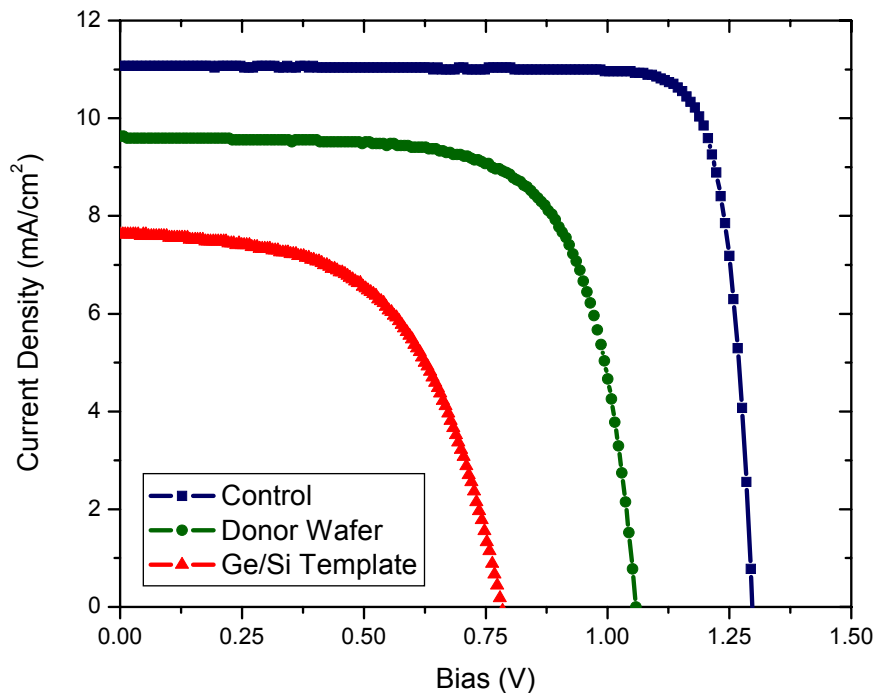
InGaAs cell	
InP	$n = 3.6$
SiO_2	$n = 3.2$
Si	$n = 1.4$





GaInP cell
GaAs cell
Ge Template
Si

GaInP Cell Performance in GaInP/GaAs/Ge/Si 2J Cell (wet etch only Ge template preparation)





 Accomplished

 In Progress

Phase 1

Task 1: Template Engineering

Fabrication of InP/Si Templates

Fabrication of Ge/Si Templates

Task 2: Subcell Design and Fabrication

Growth of double heterostructures

Development of GaInPAs/GaInAs/InP 2J cells

Development of AlGaInP/GaAs 2J cells

Phase 2

Task 3: Template Improvement

Fabrication of Improved InP/Si Templates

Fabrication of Ge/Si Templates

Task 4: Improved Subcell Design and Fabrication

Demonstrate GaInPAs/GaInAs 2J cells on bonded wafer

Demonstrate AlGaInP/GaAs 2J cells on bonded wafer

Development of AlGaInP/GaAs 2J cells

Phase 3

Task 5: 4J Integration Issues for Templates

Address Template Integration Suitability

Develop Direct Bond Interconnect

Task 6: 4J Bonded Cell Integration

Fabricate Integration-ready GaInPAs/GaInAs 2J cells

Fabricate Integration-ready AlGaInP/GaAs 2J cells



- Subcontract has established the basic viability of bonding as integration approach for lattice-mismatched multijunction cells.
- Near future (6 months) will focus on completion of wafer-bonded subcells and demonstrated of a 3J cell with Ge and InP templated layers and a direct bond interconnect.
- Follow-on research proposed for new solicitation will carry forward the knowledge and experience gain to fabricate direct bonded multijunction cells using other thin wafer approaches (ELO, substrate removal).